Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/783,373	OZAWA ET AL.
Examiner	Art Unit
Huan H. Tran	2861

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
EAST text search (USPAT;US_PGPUB,JPO;EOP;DER WENT;IBM_TDB)_see search history printout	2/15/2006	ннт
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